

Supplementary Information

Calculation of the Electronic Parameters of an Al/DNA/p-Si Schottky Barrier Diode Influenced by Alpha Radiation. *Sensors* 2015, 15, 4810-4822

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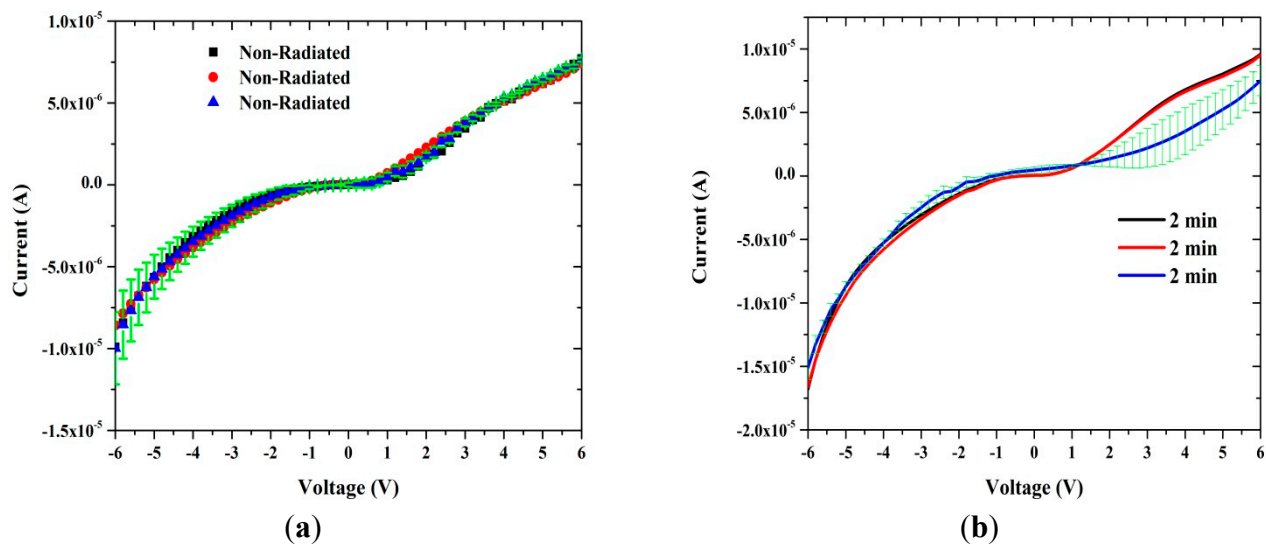
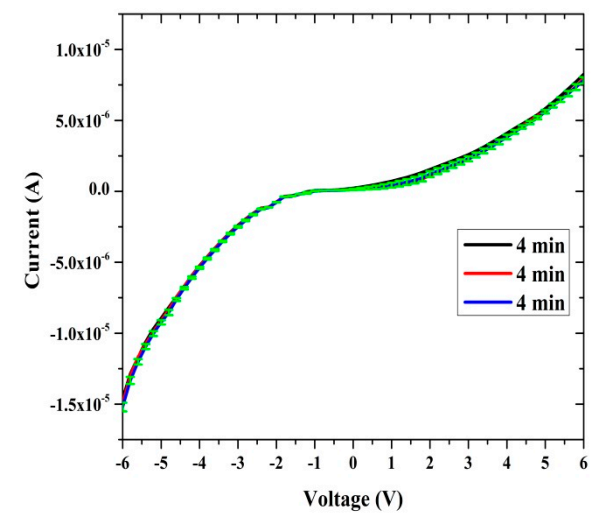
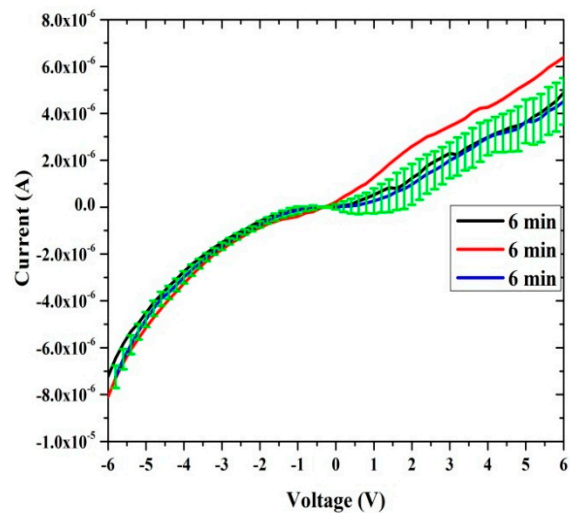


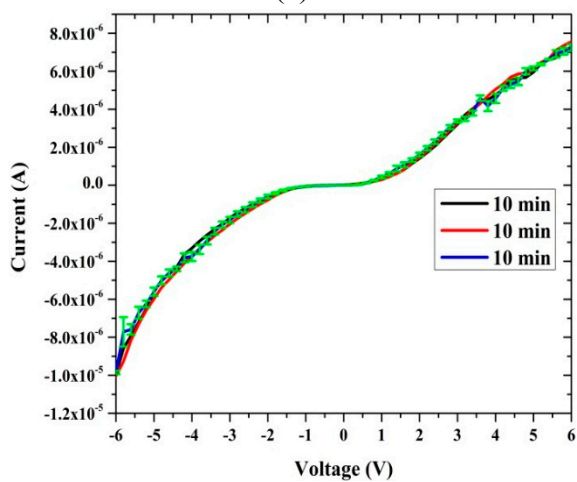
Figure S1. Cont.



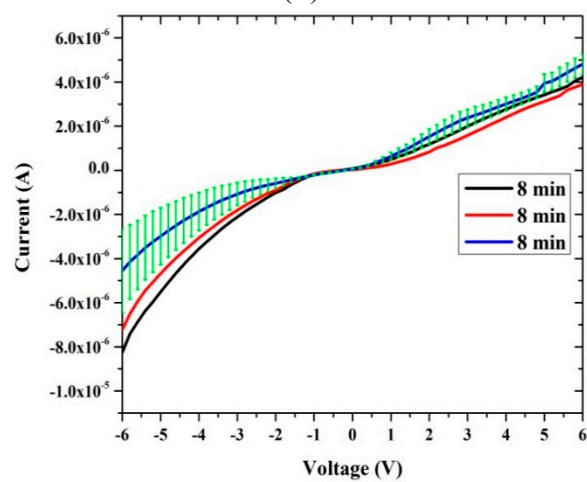
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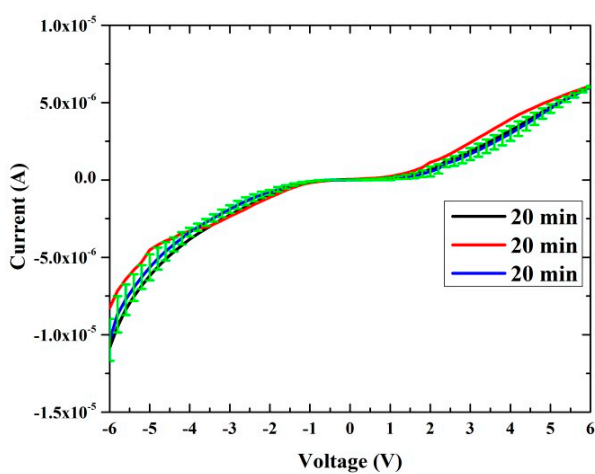
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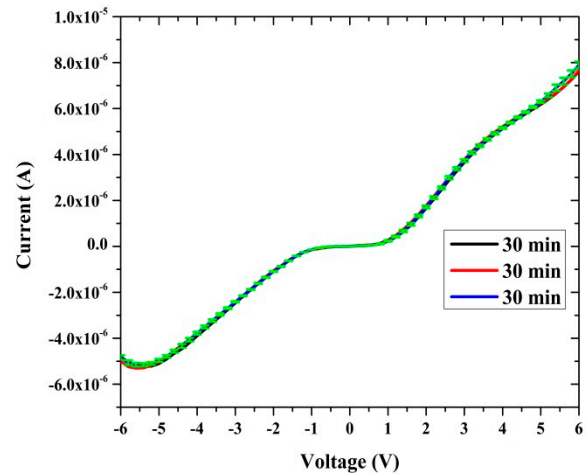
(e)



(f)

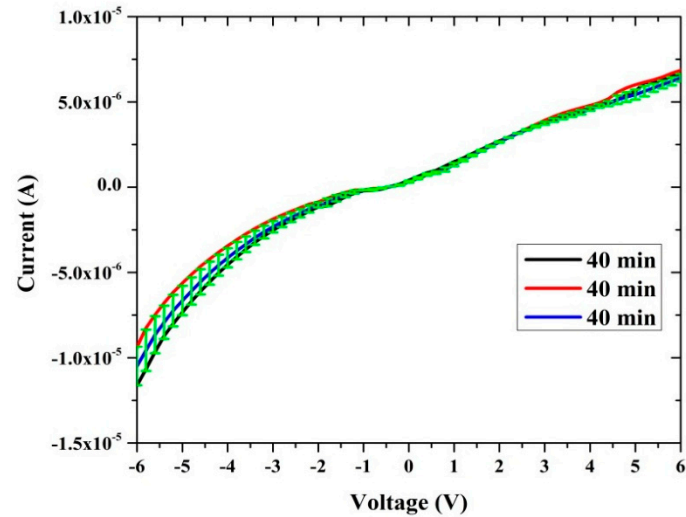


(g)



(h)

Figure S1. Cont.



(i)

Figure S1. The I-V graphs demonstrate error bars for (a) non-radiated; (b) 2 min; (c) 4 min; (d) 6 min (e) 8 min; (f) 10 mi; (g) 20 min; (h) 30 min and (i) 40 min.

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